MOSFET - Power, N-Channel, Automotive SUPERFET[®] III, Easy-Drive 650 V, 72 mΩ, 44 A

NVB072N65S3

Description

SuperFET III MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss provide superior switching performance, and with-stand extreme dv/dt rate. Consequently, SuperFET III MOSFET Easy-drive series helps manage EMI issues and allows for easier design implementation.

Features

- AEC-Q101 Qualified
- Max Junction Temperature 150°C
- Typ. $R_{DS}(on) = 61 \text{ m}\Omega$
- Ultra Low Gate Charge (Typ. $Q_G = 82 \text{ nC}$)
- Low Effective Output Capacitance (Typ. C_{OSS}(eff.) = 724 pF)
- 100% Avalanche Tested
- These Devices are Pb-Free and are RoHS Compliant

Typical Applications

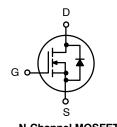
- Automotive PHEV-BEV DC-DC Converter
- Automotive Onboard Charger for PHEV-BEV



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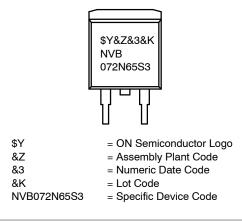
BV _{DSS}	R _{DS(on)} MAX	I _D MAX		
650 V	72 mΩ @ 10 V	44 A		



N-Channel MOSFET



MARKING DIAGRAM



ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

Symbol		Value	Unit	
V _{DSS}	Drain to Source Voltage		650	V
V _{GSS}	Gate to Source Voltage	DC	±30	V
		AC (f > 1 Hz)	±30	V
I _D	Drain Current	Continuous (T _C = 25°C)	44	А
		Continuous (T _C = 100°C)	28	А
I _{DM}	Pulsed Drain Current	Pulsed (Note 1)	110	А
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		214	mJ
E _{AR}	Repetitive Avalanche (Note 1)		3.12	mJ
dv/dt	MOSFET dv/dt		100	V/ns
	Peak Diode Recovery dv/dt (Note	20	V/ns	
PD	Power Dissipation	(T _C = 25°C)	312	W
		Derate Above 25°C	2.5	W/°C
T _J ,T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds		300	°C

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C, Unless otherwise specified)

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected. 1. Repetitive rating: pulse-width limited by maximum junction temperature. 2. $I_{AS} = 4.8 \text{ A}$, $R_G = 25 \Omega$, starting $T_J = 25^{\circ}C$. 3. $I_{SD} < 44 \text{ A}$, di/dt $\leq 200 \text{ A/ms}$, VDD $\leq \text{BVDSS}$, starting $T_J = 25^{\circ}C$.

4. Essentially independent of operating temperature typical characteristics.

THERMAL CHARACTERISTICS

Symbol	Symbol Parameter		Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.37	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Minimum Pad of 2-oz Copper), Max.		°C/W
$R_{\theta JA}$	R _{0JA} Thermal Resistance, Junction to Ambient (1 in ² Pad of 2-oz Copper), Max.		°C/W

PACKAGE MARKING AND ORDERING INFORMATION

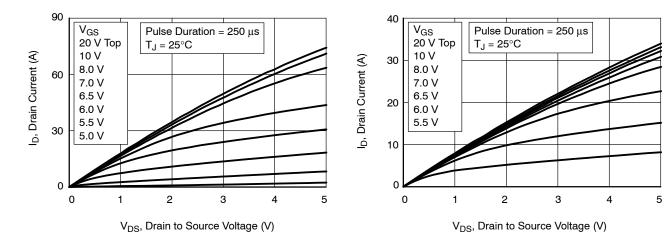
Part Number	Top Marking	Package	Packing Method	Reel Size	Tape Width	Quantity
NVB072N65S3	NVB072N65S3	D ² PAK-3	Tape and Reel	330 mm	24 mm	800 units

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Symbol	Parameter Test Conditions		Min	Тур	Max	Unit
OFF CHARACTI	ERISTICS					
BV _{DSS} Dr	Drain-to-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 1 \text{ mA}, \text{ T}_{J} = 25^{\circ}\text{C}$	650	-	-	V
		$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 1 \text{ mA}, \text{ T}_{J} = 150^{\circ}\text{C}$	700	-	-	V
∆BVDSS / ∆TJ	Breakdown Voltage Temperature Coefficient	$I_D = 1$ mA, Referenced to 25°C	-	0.60	-	V/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 650 \text{ V}, V_{GS} = 0 \text{ V}$	-	0.30	1	μA
		V_{DS} = 520 V, V_{GS} = 0 V, Tc = 125°C	-	7.30	-	
I _{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 30$ V, $V_{DS} = 0$ V	-	-	±100	nA
ON CHARACTE	RISTICS	•	-			
V _{GS(th)}	Gate to Source Threshold Voltage $V_{GS} = V_{DS}$, $I_D = 1.0$ mA		2.5	-	4.5	V
R _{DS(on)}	Static Drain to Source On Resistance	V_{GS} = 10 V, I_{D} = 22 A, T_{J} = 25°C	-	61	72	mΩ
		V_{GS} = 10 V, I _D = 22 A, T _J = 100°C	-	107	-	mΩ
9 FS	Forward Transconductance	V _{DS} = 20 V, I _D = 44 A	-	29.7	-	S
YNAMIC CHAR	RACTERISTICS	•				
C _{iss}	Input Capacitance	V _{DS} = 400 V, V _{GS} = 0 V, f = 1 MHz	-	3300	-	pF
C _{oss}	Output Capacitance	1	-	72.8	-	pF
C _{rss}	Reverse Transfer Capacitance		-	14.6	-	pF
C _{oss(eff.)}	Effective Output Capacitance	V_{DS} = 0 V to 400 V, V_{GS} = 0 V	-	724	-	pF
C _{oss(er.)}	Energy Related Output Capacitance	V_{DS} = 0 V to 400 V, V_{GS} = 0 V	-	104	-	pF
Q _{g(tot)}	Total Gate Charge	V _{DS} = 400 V, V _{GS} = 10 V, I _D = 44 A	-	82.0	-	nC
Q _{gs}	Gate to Source Gate Charge	(Note 4)	-	23.3	-	nC
Q _{gd}	Gate to Drain "Miller" Charge		-	34.0	-	nC
R _G	Gate Resistance	f = 1 MHz	-	0.685	-	Ω
WITCHING CH	ARACTERISTICS	•				
t _{d(on)}	Turn–On Delay Time	V_{DD} = 400 V, I_{D} = 44 A, V_{GS} = 10 V,	-	26.3	-	ns
t _r	Turn-On Rise Time	R _G = 4.7 Ω (Note 4)	-	50	-	ns
t _{d(off)}	Turn-Off Delay Time		-	65.9	-	ns
t _f	Fall Time		-	32	-	ns
RAIN-SOURC	E DIODE CHARACTERISTICS		-			
۱ _S	Maximum Continuous Drain to Source Diode Forward Current			-	44	Α
I _{SM}	Maximum Plused Drain to Source Diode Forward Current			-	110	Α
V _{SD}	Drain to Source Diode Forward Voltage	$V_{GS} = 0 V, I_{SD} = 22 A$	-	-	1.2	V
t _{rr}	Reverse Recovery Time	V_{GS} = 0 V, I _{SD} = 44 A dI _F /dt = 100 A/µs	-	576	-	nS
Q _{rr}	Reverse Recovery Charge	1	-	14.3	-	μC

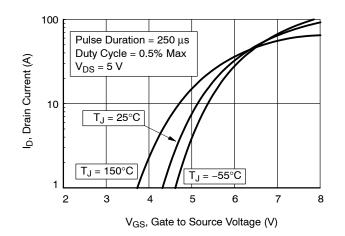
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

TYPICAL CHARACTERISTICS

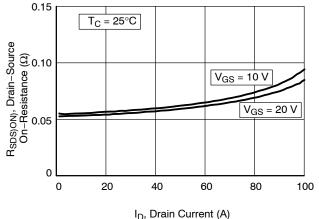


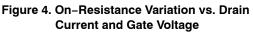












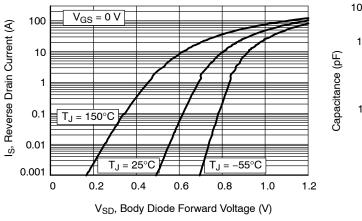
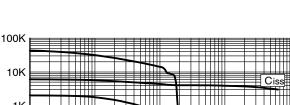
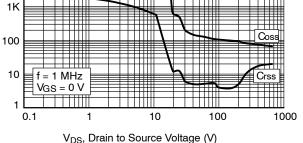
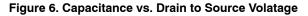


Figure 5. Forward Diode Characteristics







TYPICAL CHARACTERISTICS (continued)

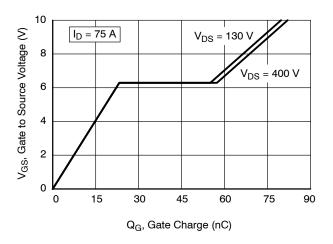


Figure 7. Gate Charge vs. Gate to Source Voltage

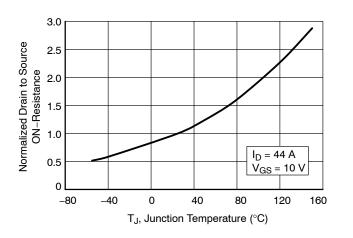


Figure 9. Normalized R_{DSON} vs. Junction Temperature

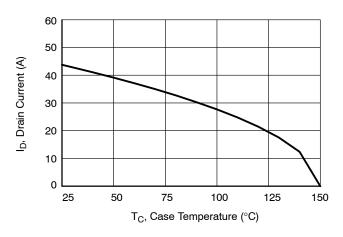


Figure 11. Maximum Continuous Drain Current vs. Case Temperature

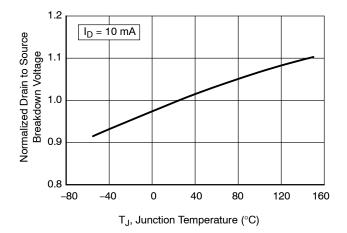


Figure 8. Normalized Drain to Source Breakdown Voltage vs. Junction Temperature

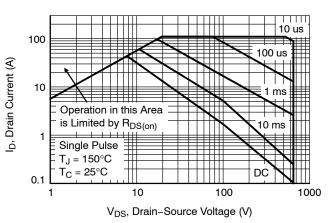
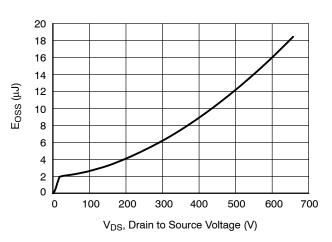
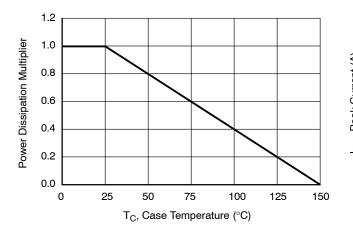


Figure 10. Forward Bias Safe Operating Area





TYPICAL CHARACTERISTICS (continued)



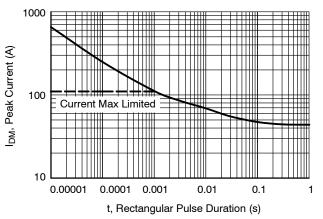
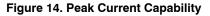


Figure 13. Normalized Power Dissipation vs. Case Temperature



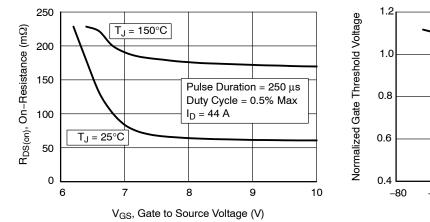


Figure 15. On-Resistance vs. Gate to Source Voltage

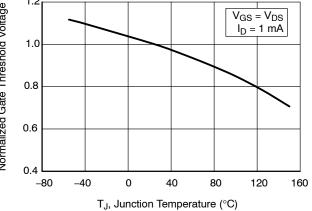
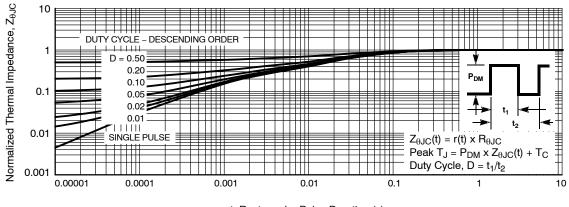


Figure 16. Normalized Gate Threshold Voltage vs. Temperature



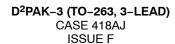
t, Rectangular Pulse Duration (s)

Figure 17. Normalized Maximum Transient Thermal Impedance

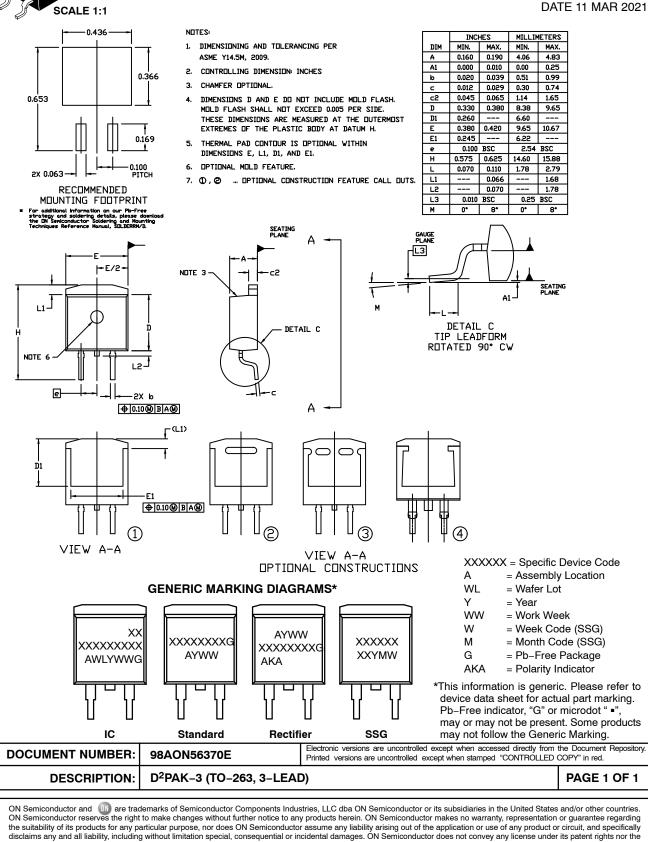
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MECHANICAL CASE OUTLINE PACKAGE DIMENSIONS









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